Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
09/382,371	PHILYAW ET AL.
Examiner	Art Unit
Hai V. Nguyen	2142

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Class	Subclass	Date	Examiner
ALL	UPDATED	1/9/2007	HN
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
EAST search updated (US-PGPUB; USPAT; USOCR; EPO;JPO;DERWENT; IBM-TDB) (see search history printout report)	1/9/2007	HN	
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